



MACRONIX
INTERNATIONAL Co., LTD.

Quality & Reliability Quarterly Report

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1. Quality/Reliability Monitoring Test Items and Conditions:

Test Item	Test Method	Test Conditions	Typical Sample Size (units)
Quality Validation (QV)	JESD86	DC/AC tests for full range temperature, Vcc/Vpp, refer to datasheet	All samples
Early Life Failure Rate (ELFR)	JESD22-A108 and JESD74	125°C, Vcc(max), 48 hrs	2000
Non-Volatile Memory Cycling Endurance (NVCE)	JESD47 JESD22-A117 (For Industrial Product)	Half samples at 25 °C, half samples at max operating Temperature, 1K/10K/100K Program/Erase cycles. (NAND: 10%/100% cycles of max endurance specification.) For flash products only.	77
NVM Endurance, Data Retention and Operational Life (EDR)	AEC-Q100-005 (For Automotive Product)	77units at 25 °C / 154 units at ≥85 °C to max cycling spec per note. For flash products only.	231
Nonvolatile Memory Low-Temperature Data Retention and Read Disturb (LTDDR)	JESD47 JESD22-A117 (For Industrial Product)	25 °C, Vcc(max), cycles per NVCE (≥25 °C), 168hrs/500hrs. For flash products only.	77
Low Temperature Data Retention (LTDR)	AEC-Q100-005 (For Automotive Product)	25 °C, Vcc(max), cycles per NVCE (25 °C), 168hrs/500hrs/1000hrs. For flash products only.	77
Nonvolatile Memory Post-cycling High Temperature Data Retention (PCHTDR)	JESD47 JESD22-A117 (For Industrial Product)	125°C, cycles per NVCE (≥55 °C), 10hrs/100hrs. (at 10 hours if cycles to max spec, at 100 hours if cycles ≤10% max. spec) (NAND SLC at 100 hours if cycles ≤1% max. spec). For flash products only.	77
High Temperature Data Retention (HTDR)	AEC-Q100-005 (For Automotive Product)	125°C for plastic package, cycles per NVCE (≥55 °C), 10hrs/100hrs. (If product spec define the retention lifetime fitting to >55 °C, QRE defines the bake time per datasheet definition and Ea). For flash products only.	77
High Temperature Operating Life (HTOL)	JESD22-A108 and JESD85 AEC-Q100-005 (For Automotive Product)	125°C, Vcc(max), 168hrs/500hrs/1000hrs	77 Automotive Product:77
High Temperature Storage Life (HTSL)	JESD22-A103	150°C, 168hrs/500hrs/1000hrs	77
Preconditioning (PC) SMD only	JESD22-A113 J-STD-020	Refer to OI# 5650-0901(must be done before HAST/AC/TC for SMDs)	All the SMD qual samples for package tests
Temperature Cycling (TC)	JESD22-A104 condition C	-65°C to 150°C, 200/500 cycles	77



Highly-Accelerated Temperature and Humidity Stress (HAST)	JESD22-A110	130°C, 85% RH, Vcc(max), 96hrs	77
Autoclave (AC) or Unbiased HAST (UHAST)	JESD22-A102 JESD22-A118	121°C /100%RH, 96 hrs or 130°C / 85%RH, 96 hrs	77

2. Flash Quarterly Reliability Monitor Results:

2-1. Quality Validation & Early Life Failure Rate:

Tech.	EPN Code	QV		ELFR	
		SS	Reject	SS	Reject
150 nm	MX29LV400C	4000	0	2000	0
130 nm	MX29LV160D	4000	0	4000	0
110 nm	MX25L6445E	4000	0	4000	0
	MX25L3206E	4000	0	4000	0
	MX25U1635E	4000	0	4000	0
	MX25L6445E	1200	0	*2	*2
	MX25L3235E	1200	0	*2	*2
	MX25U3235E	1200	0	*2	*2
75 nm	MX25L12833F	4000	0	4000	0
	MX25L12835F	4000	0	4000	0
	MX25R8035F	4000	0	2000	0
	MX25U12832F	4000	0	4000	0
	MX25S6433F	6000	0	6000	0
	MX25L12833F	1200	0	*2	*2
	MX25L3233F	1200	0	*2	*2
	MX25V1635F	1200	0	*2	*2
68 nm	MX25U12832F	1200	0	*2	*2
	MX25V16066M	8000	0	6000	0
55 nm	MX25L25645G	4000	0	4000	0
	MX25U51245G	4000	0	2000	0
	MX25L25645G	1200	0	*2	*2
	MX25U51245G	1200	0	*2	*2
45 nm	MX25L51245J	4000	0	*1	*1
36 nm	MX30LF1G18AC	4000	0	2000	0
	MX30LF4G18AC	1200	0	*2	*2
19 nm	MX30LMBGX8AA	4000	0	2000	0
	MX30LF2G28AD	4000	0	4000	0
	MX30UF4G28AD	4000	0	2000	0

*1: Means the test is “on going”. The results will be updated next quarter.

*2: No ELFR test, the samples are only used for QV and NVCE test.



2-2. Non-Volatile Memory Cycling Endurance:

Tech.	EPN Code	NVCE@25°C		NVCE@85°C	
		SS	Reject	SS	Reject
150 nm	MX29LV400C	308	0	154	0
130 nm	MX29LV160D	76	0	78	0
110 nm	MX25L6445E	76	0	78	0
	MX25L3206E	76	0	78	0
	MX25U1635E	76	0	78	0
75 nm	MX25L12833F	76	0	78	0
	MX25L12835F	76	0	78	0
	MX25R8035F	76	0	78	0
	MX25U12832F	76	0	78	0
	MX25S6433F	114	0	117	0
68 nm	MX25V16066M	152	0	156	0
55 nm	MX25L25645G	76	0	78	0
	MX25U51245G	76	0	78	0
45 nm	MX25L51245J	38	0	39	0
36 nm	MX30LF1G18AC	38	0	78	0
19 nm	MX30LMBGX8AA	76	0	78	0
	MX30LF2G28AD	76	0	78	0
	MX30UF4G28AD	38	0	39	0

2-3. Data Retention:

Tech.	EPN Code	LTDDR@25°C 500hrs		PCHTDR@125°C 100hrs	
		SS	Reject	SS	Reject
130 nm	MX29LV160D	76	0	78	0
110 nm	MX25L6445E	76	0	78	0
	MX25L3206E	76	0	78	0
	MX25U1635E	38	0	39	0
75 nm	MX25L12833F	76	0	78	0
	MX25L12835F	76	0	78	0
	MX25R8035F	38	0	78	0
	MX25U12832F	76	0	78	0
	MX25S6433F	76	0	117	0
68 nm	MX25V16066M	114	0	117	0
55 nm	MX25L25645G	76	0	78	0
	MX25U51245G	38	0	78	0
45 nm	MX25L51245J	*1	*1	*1	*1
36 nm	MX30LF1G18AC	38	0	39	0
19 nm	MX30LMBGX8AA	38	0	39	0
	MX30LF2G28AD	76	0	78	0
	MX30UF4G28AD	38	0	39	0

*1: Means the test is "on going". The results will be updated next quarter.



2-4. Non-Volatile Memory Program/ Erase Endurance, Data Retention and Operation Life (For Automotive Product):

a. High Temperature

Tech.	EPN Code	EDR@125°C		HTDR@150°C 500hrs		HTOL@125°C 1000hrs	
		SS	Reject	SS	Reject	SS	Reject
110 nm	MX25L6445E	308	0	154	0	154	0
	MX25L3235E	308	0	154	0	154	0
75 nm	MX25L12833F	308	0	77	0	77	0
	MX25L3233F	308	0	154	0	154	0
	MX25V1635F	308	0	154	0	154	0
	MX25U12832F	308	0	154	0	77	0
55 nm	MX25L25645G	308	0	77	0	77	0
	MX25U51245G	308	0	154	0	154	0

Tech.	EPN Code	EDR @105°C		HTDR@150°C 500hrs		HTOL@125°C 1000hrs	
		SS	Reject	SS	Reject	SS	Reject
110 nm	MX25U3235E	308	0	154	0	154	0

Tech.	EPN Code	EDR@105°C		HTDR@150°C 100hrs		HTOL@125°C 1000hrs	
		SS	Reject	SS	Reject	SS	Reject
36 nm	MX30LF4G18AC	308	0	154	0	77	0

b. Low Temperature

Tech.	EPN Code	EDR@25°C		LTDR@25°C 1000hrs	
		SS	Reject	SS	Reject
110 nm	MX25L6445E	154	0	154	0
	MX25L3235E	154	0	154	0
	MX25U3235E	154	0	154	0
75 nm	MX25L12833F	154	0	77	0
	MX25L3233F	154	0	154	0
	MX25V1635F	154	0	154	0
	MX25U12832F	154	0	77	0
55 nm	MX25L25645G	154	0	77	0
	MX25U51245G	154	0	154	0
36 nm	MX30LF4G18AC	154	0	77	0



2-5. High Temperature Operating Life and High Temperature Storage Life:

Tech.	EPN Code	HTOL 1000hrs		HTSL 1000hrs	
		SS	Reject	SS	Reject
150 nm	MX29LV400C	77	0	154	0
130 nm	MX29LV160D	154	0	154	0
110 nm	MX25L6445E	154	0	154	0
	MX25L3206E	154	0	154	0
	MX25U1635E	77	0	154	0
75 nm	MX25L12833F	77	0	154	0
	MX25L12835F	154	0	154	0
	MX25R8035F	77	0	154	0
	MX25U12832F	154	0	154	0
	MX25S6433F	154	0	231	0
68 nm	MX25V16066M	231	0	231	0
55 nm	MX25L25645G	77	0	154	0
	MX25U51245G	77	0	154	0
45 nm	MX25L51245J	77	0	*1	*1
36 nm	MX30LF1G18AC	77	0	77	0
19 nm	MX30LMBGX8AA	77	0	77	0
	MX30LF2G28AD	154	0	154	0
	MX30UF4G28AD	77	0	77	0

*1: Means the test is “on going”. The results will be updated next quarter.



2-6. Pre-Condition / Autoclave / Temperature Cycling / Highly Accelerated Temperature and Humidity Stress:

Tech.	EPN Code	PC		TC 500cycles		AC 96hrs		HAST 96hrs	
		SS	Reject	SS	Reject	SS	Reject	SS	Reject
150 nm	MX29LV400C	462	0	154	0	154	0	154	0
130 nm	MX29LV160D	462	0	154	0	154	0	154	0
110 nm	MX25L6445E	462	0	154	0	154	0	154	0
	MX25L3206E	462	0	154	0	154	0	154	0
	MX25U1635E	462	0	154	0	154	0	154	0
75 nm	MX25L12833F	462	0	154	0	154	0	154	0
	MX25L12835F	462	0	154	0	154	0	154	0
	MX25R8035F	462	0	154	0	154	0	154	0
	MX25U12832F	462	0	154	0	154	0	154	0
	MX25S6433F	693	0	231	0	231	0	231	0
68 nm	MX25V16066M	924	0	308	0	308	0	308	0
55 nm	MX25L25645G	462	0	154	0	154	0	154	0
	MX25U51245G	462	0	154	0	154	0	154	0
45 nm	MX25L51245J	462	0	154	0	154	0	154	0
36 nm	MX30LF1G18AC	462	0	154	0	154	0	154	0
19 nm	MX30LMBGX8AA	462	0	77	0	77	0	77	0
	MX30LF2G28AD	462	0	154	0	154	0	154	0
	MX30UF4G28AD	231	0	77	0	77	0	77	0